

Using Design of Experiments (DOE) to Integrate Developmental and Operational T&E

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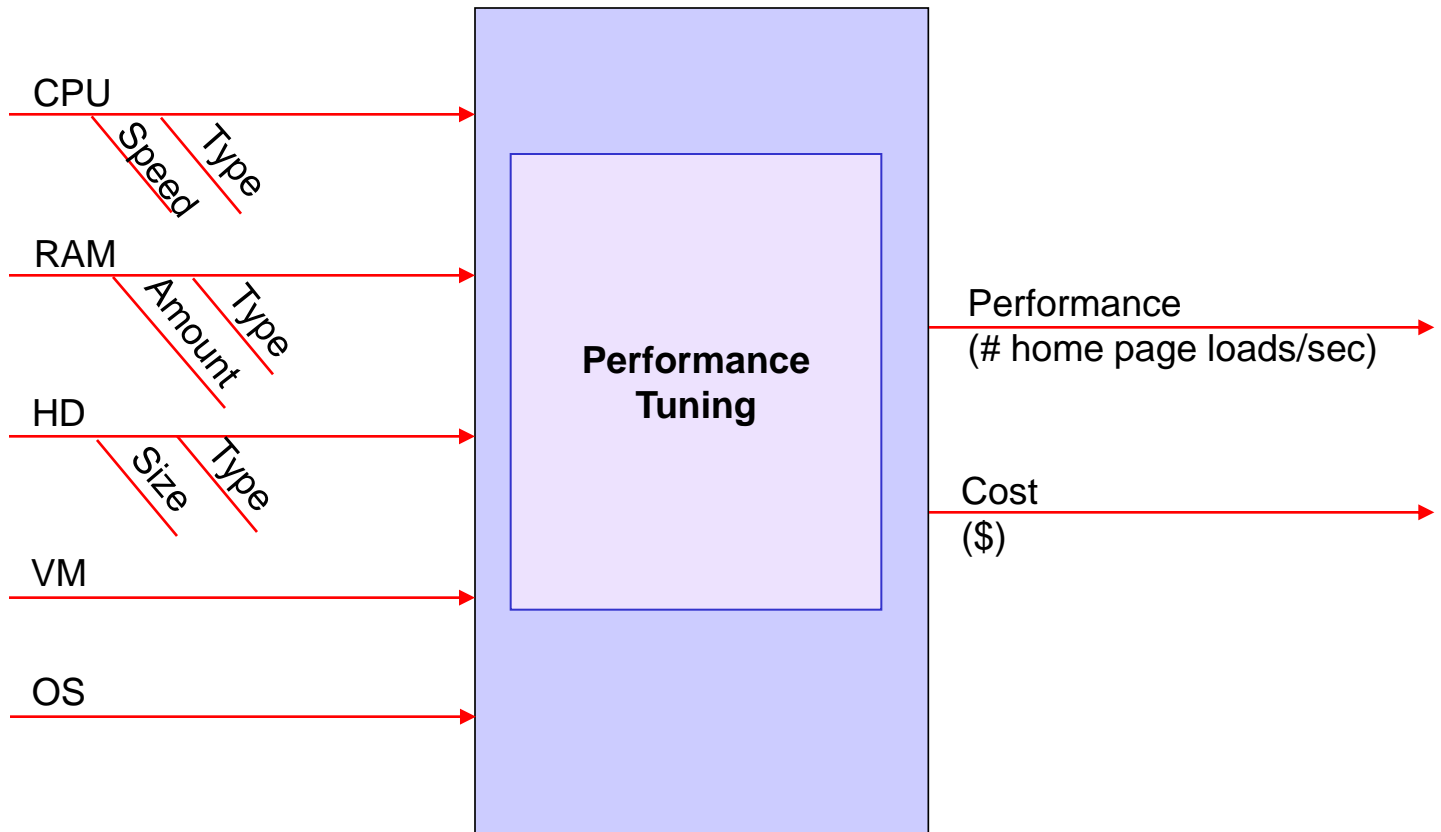
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11-DOELE-3A

Agenda

- **Various Approaches to Testing Multiple Factors**
- **What makes Design of Experiments so special?**
- **Using DOE to build transfer functions in DT&E**
- **Critical Parameter Management: linking the functions together**
- **High Throughput Testing in OT&E**

Web-Based Test Scenario



Performance Tuning Terminology

Factors/Inputs (X's)	Levels (Choices)	Performance/Outputs (Y's)
CPU Type	Itanium, Xeon	# home page loads/sec
CPU Speed	1 GHz, 2.5 GHz	Cost
RAM Amount	256 MB, 1.5 GB	
HD Size	50 GB, 500 GB	
VM	J2EE, .NET	
OS	Windows, Linux	

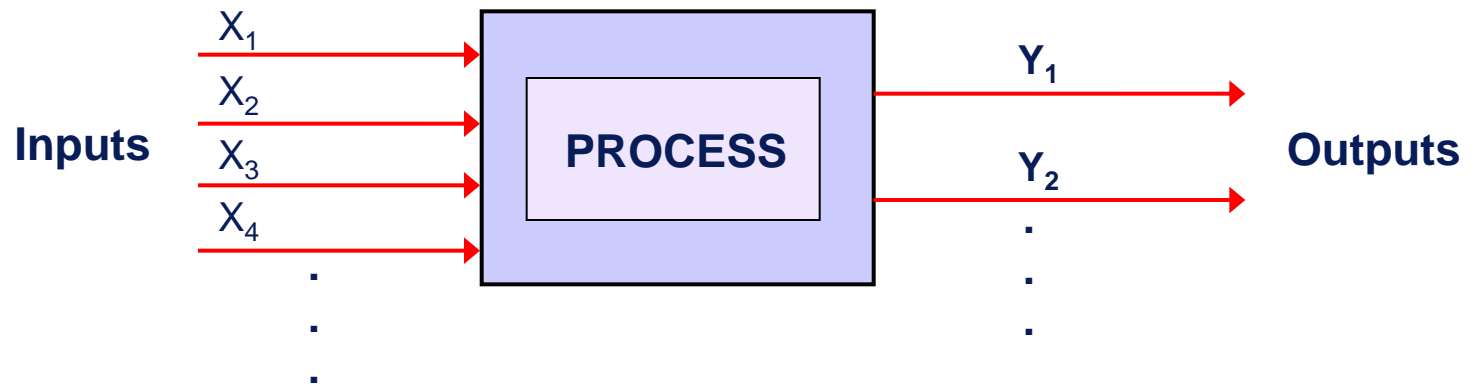
Which factors are important? Which are not?
Which combination of factor choices will maximize performance?
How do you know for sure? Show me the data.

Approaches to Testing Multiple Factors

- **Traditional Approaches**
 - One Factor at a Time (OFAT)
 - Oracle (Best Guess)
 - All possible combinations (full factorial)
- **Modern Approach**
 - Statistically designed experiments (DOE) ... full factorial plus other selected DOE designs, depending on the situation

What is a Designed Experiment?

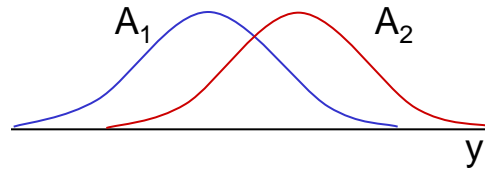
Purposeful changes of the inputs (factors) in order to observe corresponding changes in the output (response).



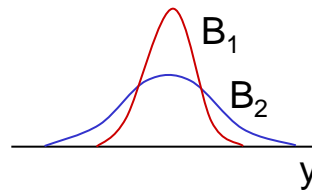
Run	X_1	X_2	X_3	X_4	Y_1	Y_2	\bar{Y}	S_Y
1									
2									
3									
.									
.									

DOE Helps Determine How Inputs Affect Outputs

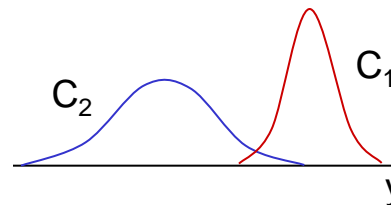
i) Factor A affects the average of y



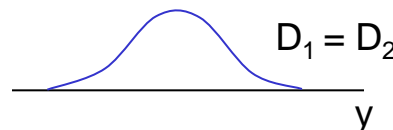
ii) Factor B affects the standard deviation of y



iii) Factor C affects the average and the standard deviation of y

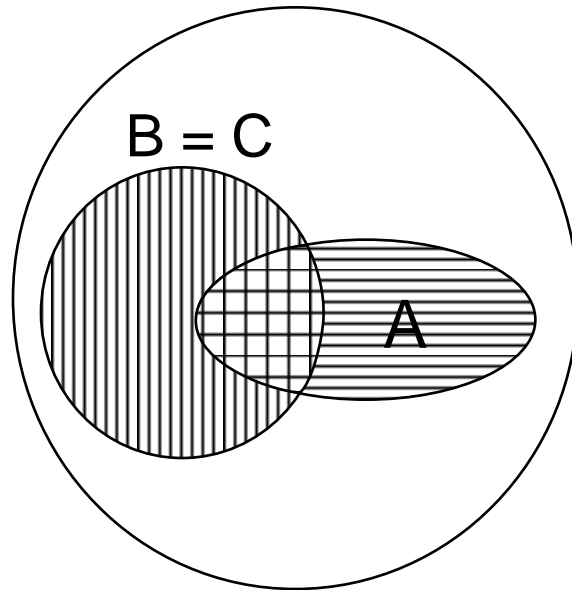


iv) Factor D has no effect on y

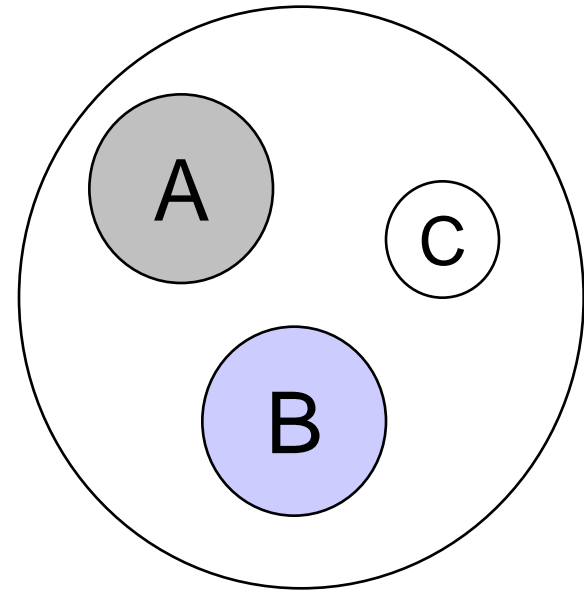


Evaluating the Effects of Variables on Y

We don't want this:



What we need is a design to provide independent estimates of effects:



How do we obtain this independence of variables?

Statistically Designed Experiments (DOE): Orthogonal or Nearly Orthogonal Designs

- FULL FACTORIALS (for small numbers of factors)
- FRACTIONAL FACTORIALS
- PLACKETT - BURMAN
- LATIN SQUARES
- HADAMARD MATRICES
- BOX - BEHNKEN DESIGNS
- CENTRAL COMPOSITE DESIGNS
- NEARLY ORTHOGONAL LATIN HYPERCUBE DESIGNS

} Taguchi Designs

SIMPLE DEFINITION OF TWO-LEVEL ORTHOGONAL DESIGNS

Run	Actual Settings			Coded Matrix			Responses
	(5, 10) A: Time	(70, 90) B: Temp	(100,200) C: Press	(A) Time	(B) Temp	(C) Press	
1	5	70	100	-1	-1	-1	
2	5	70	200	-1	-1	+1	
3	5	90	100	-1	+1	-1	
4	5	90	200	-1	+1	+1	
5	10	70	100	+1	-1	-1	
6	10	70	200	+1	-1	+1	
7	10	90	100	+1	+1	-1	
8	10	90	200	+1	+1	+1	

What Makes DOE so Powerful? (Orthogonality: both vertical and horizontal balance)

A Full Factorial Design for 3 Factors A, B, and C, Each at 2 levels:

Run	A	B	C	AB	AC	BC	ABC
1	-	-	-	+	+	+	-
2	-	-	+	+	-	-	+
3	-	+	-	-	+	-	+
4	-	+	+	-	-	+	-
5	+	-	-	-	-	+	+
6	+	-	+	-	+	-	-
7	+	+	-	+	-	-	-
8	+	+	+	+	+	+	+

Design of Experiments (DOE)

- An optimal data collection methodology
- “Interrogates” the process
- Used to identify important relationships between input and output factors
- Identifies important interactions between process variables
- Can be used to optimize a process
- Changes “I think” to “I know”

Google on DOE

(quotes* from Daryl Pregibon, Google Engineer)

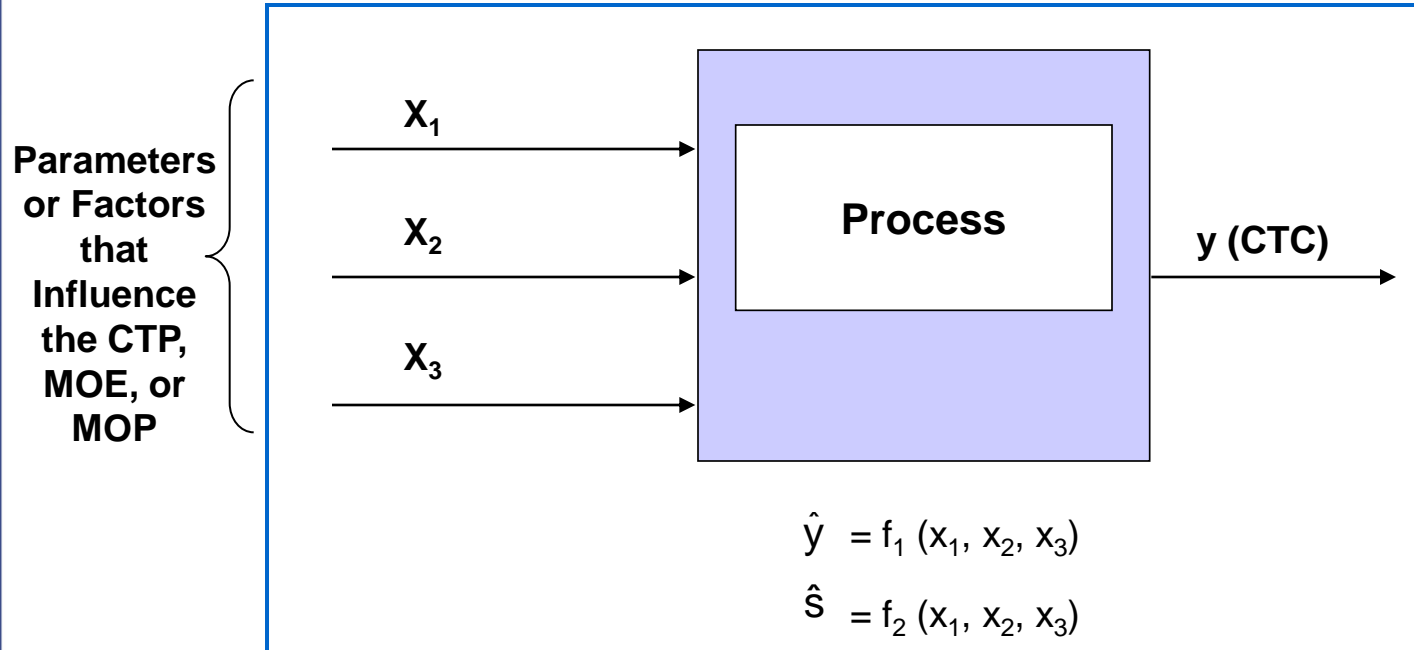
“From a user’s perspective, a query was submitted and results appear. From Google’s perspective, the user has provided an opportunity to test something. What can we test? Well, there is so much to test that we have an Experiment Council that vets experiment proposals and quickly approves those that pass muster.”

“ We evangelize experimentation to the extent that we provide a mechanism for advertisers to run their own experiments.

. . . allows an advertiser to run a (full) factorial experiment on its web page. Advertisers can explore layout and content alternatives while Google randomly directs queries to the resulting treatment combinations. Simple analysis of click and conversion rates allows advertisers to explore a range of alternatives and their effect on user awareness and interest.”

*** Taken From: *Statistics @ Google* in Amstat News, May 2011**

Transfer Function: A Key DT and OT Concept

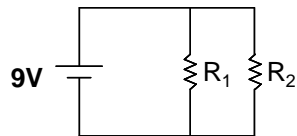


Where does the transfer function come from?

- **Exact transfer function**
- **Approximations**
 - **DOE**
 - **Historical Data Analysis**
 - **Simulation**

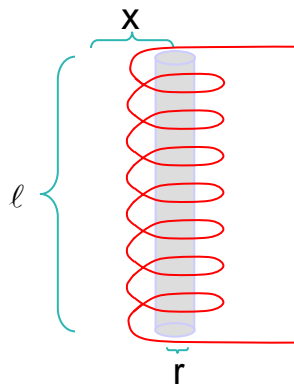
Exact Transfer Functions

- Engineering Relationships
 - $V = IR$
 - $F = ma$



The equation for current (I) through this DC circuit is defined by:

$$I = \frac{V}{R_1 + R_2} = \frac{V(R_1 \cdot R_2)}{R_1 \cdot R_2 + R_1 \cdot R_2}$$



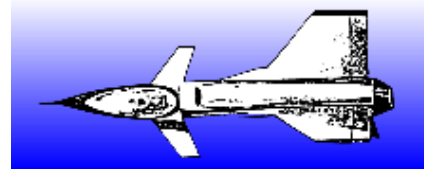
The equation for magnetic force at a distance X from the center of a solenoid is:

$$H = \frac{NI}{2l} \left[\frac{.5l + x}{\sqrt{r^2 + (.5l + x)^2}} + \frac{.5l - x}{\sqrt{r^2 + (.5l - x)^2}} \right]$$

- Where
- N: total number of turns of wire in the solenoid
 - I: current in the wire, in amperes
 - r: radius of helix (solenoid), in cm
 - l : length of the helix (solenoid), in cm
 - x: distance from center of helix (solenoid), in cm
 - H: magnetizing force, in amperes per centimeter

Value Delivery: Reducing Time to Market for New Technologies

INPUT



OUTPUT

Pitch <) (0, 15, 30)

Roll <) (0, 15, 30)

W1F <) (-15, 0, 15)

W2F <) (-15, 0, 15)

W3F <) (-15, 0, 15)



Six Aero-Characteristics

Total # of Combinations = $3^5 = 243$

Central Composite Design: $n = 30$

Patent Holder: Dr. Bert Silich

Aircraft Equations

$$C_L = .233 + .008(P)^2 + .255(P) + .012(R) - .043(WD1) - .117(WD2) + .185(WD3) + .010(P)(WD3) - .042(R)(WD1) + .035(R)(WD2) + .016(R)(WD3) + .010(P)(R) - .003(WD1)(WD2) - .006(WD1)(WD3)$$

$$C_D = .058 + .016(P)^2 + .028(P) - .004(WD1) - .013(WD2) + .013(WD3) + .002(P)(R) - .004(P)(WD1) - .009(P)(WD2) + .016(P)(WD3) - .004(R)(WD1) + .003(R)(WD2) + .020(WD1)^2 + .017(WD2)^2 + .021(WD3)^2$$

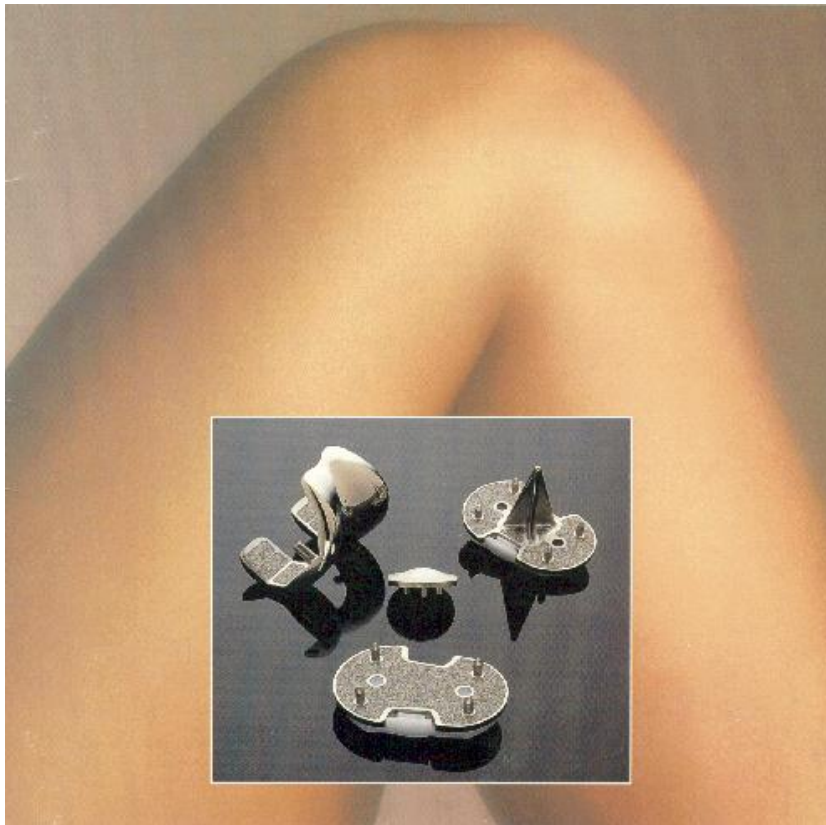
$$C_Y = -.006(P) - .006(R) + .169(WD1) - .121(WD2) - .063(WD3) - .004(P)(R) + .008(P)(WD1) - .006(P)(WD2) - .008(P)(WD3) - .012(R)(WD1) - .029(R)(WD2) + .048(R)(WD3) - .008(WD1)^2$$

$$C_M = .023 - .008(P)^2 + .004(P) - .007(R) + .024(WD1) + .066(WD2) - .099(WD3) - .006(P)(R) + .002(P)(WD2) - .005(P)(WD3) + .023(R)(WD1) - .019(R)(WD2) - .007(R)(WD3) + .007(WD1)^2 - .008(WD2)^2 + .002(WD1)(WD2) + .002(WD1)(WD3)$$

$$C_{YM} = .001(P) + .001(R) - .050(WD1) + .029(WD2) + .012(WD3) + .001(P)(R) - .005(P)(WD1) - .004(P)(WD2) - .004(P)(WD3) + .003(R)(WD1) + .008(R)(WD2) - .013(R)(WD3) + .004(WD1)^2 + .003(WD2)^2 - .005(WD3)^2$$

$$C_e = .003(P) + .035(WD1) + .048(WD2) + .051(WD3) - .003(R)(WD3) + .003(P)(R) - .005(P)(WD1) + .005(P)(WD2) + .006(P)(WD3) + .002(R)(WD1)$$

Fusing Titanium and Cobalt-Chrome



Courtesy Rai Chowdhary

DOE “Market Research” Example (cont.)

Question: Choose the best design for evaluating this scenario

Answer: L_{18} design with attributes A - H in the inner array and factors J, K, and L in the outer array, resembling an L_{18} robust design, as shown below:

Run*									L									\bar{y}	s		
	A	B	C	D	E	F	G	H	K	J	y_1	y_2	y_3	y_4	y_5	y_6	y_7			y_8	
1	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-		
2	-	-	0	0	0	0	0	0	-	+	-	-	-	-	-	-	-	-	-	Segmentation of the population or <u>Respondent Profiles</u>	
3	-	-	+	+	+	+	+	+	-	-	-	-	-	-	-	-	-	-	-		
4	-	0	-	-	0	0	+	+	-	+	-	-	-	-	-	-	-	-	-		
5	-	0	0	0	+	+	-	-	-	+	-	-	-	-	-	-	-	-	-		
6	-	0	+	+	-	-	0	0	-	-	-	-	-	-	-	-	-	-	-		
7	-	+	-	0	-	+	0	+	-	+	-	-	-	-	-	-	-	-	-		
8	-	+	0	+	0	-	+	-	-	-	-	-	-	-	-	-	-	-	-		
9	-	+	+	-	+	0	-	0	-	-	-	-	-	-	-	-	-	-	-		
10	+	-	-	+	+	0	0	-	-	-	-	-	-	-	-	-	-	-	-		
11	+	-	0	-	-	+	+	0	-	-	-	-	-	-	-	-	-	-	-		
12	+	-	+	0	0	-	-	-	-	-	-	-	-	-	-	-	-	-	-		
13	+	0	-	0	+	-	+	0	-	-	-	-	-	-	-	-	-	-	-		
14	+	0	0	+	-	0	-	+	-	-	-	-	-	-	-	-	-	-	-		
15	+	0	+	-	0	+	0	-	-	-	-	-	-	-	-	-	-	-	-		
16	+	+	-	+	0	+	-	0	-	-	-	-	-	-	-	-	-	-	-		
17	+	+	0	-	+	-	0	+	-	-	-	-	-	-	-	-	-	-	-		
18	+	+	+	0	-	0	+	-	-	-	-	-	-	-	-	-	-	-	-		

* 18 different product profiles

Modeling The Drivers of Turnover*



*Adapted from Harvard Business Review article on Boston Fleet Bank, April 2004, pp 116-125

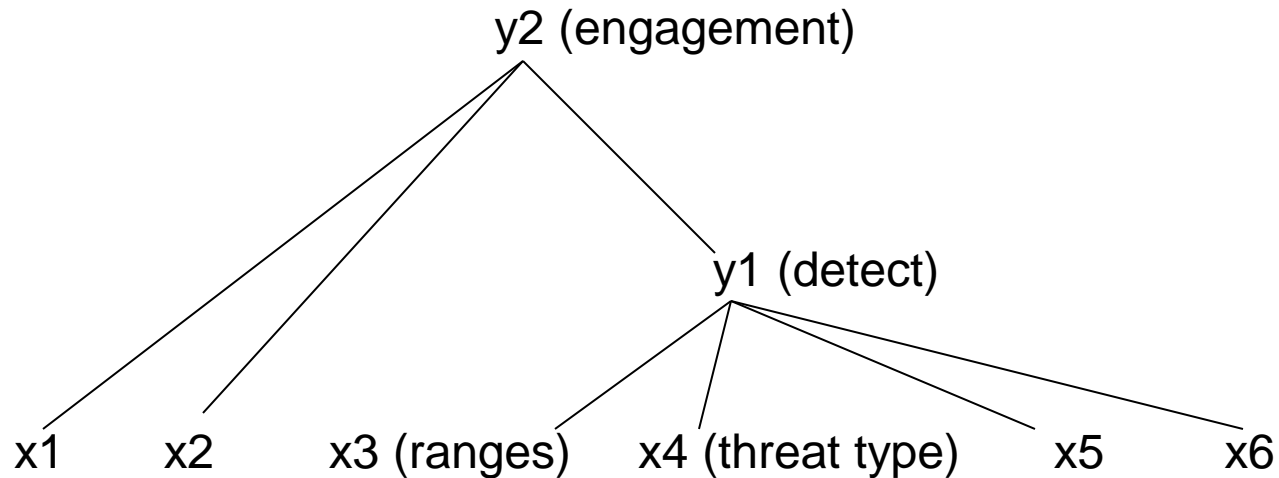
The Value of Transfer Functions

- Provide a simple and compact way of understanding relationships between performance measures or response variables (y's) and the factors (x's) that influence them.
- Allow for the prediction of the response variable (y), with associated risk levels, before any change in the product or process is made.
- Allow for the assessment of process or product capability in the presence of uncontrolled variation or noise.
- Allow the very quick manipulation of complex systems using a meta-model derived from a simulator via DOE.
- Provide a very easy way to optimize performance via robust or parameter design and tolerance allocation.
- Make sensitivity analysis easy and straightforward.
- Greatly enhance one's knowledge of a product or process.
- In general, they are the gateway to systematic innovation.
- Provide a meaningful metric for the maturity in DFSS for any organization.

Critical Parameter Management and COIs

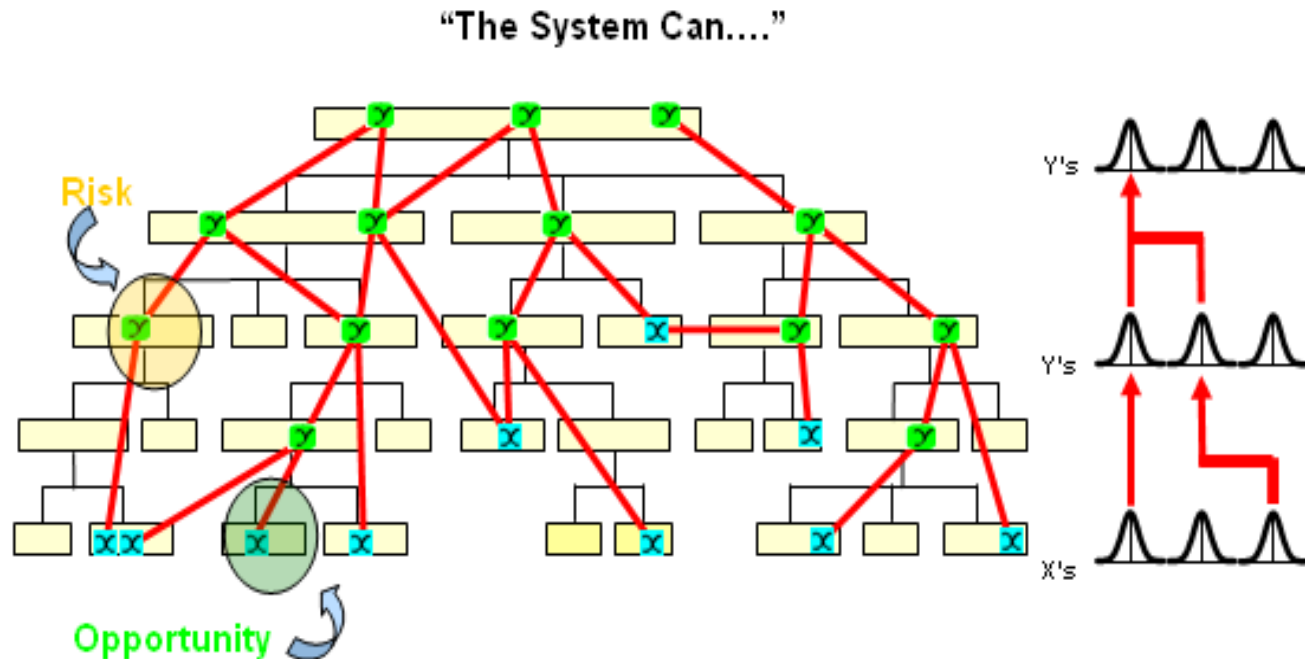
- A Critical Operational Issue (COI) is linked to operational effectiveness and suitability.
- It is typically phrased as a question, e.g.,

Will the system **detect** the **threat** in a **combat environment** at adequate **range** to allow for successful **engagement**?

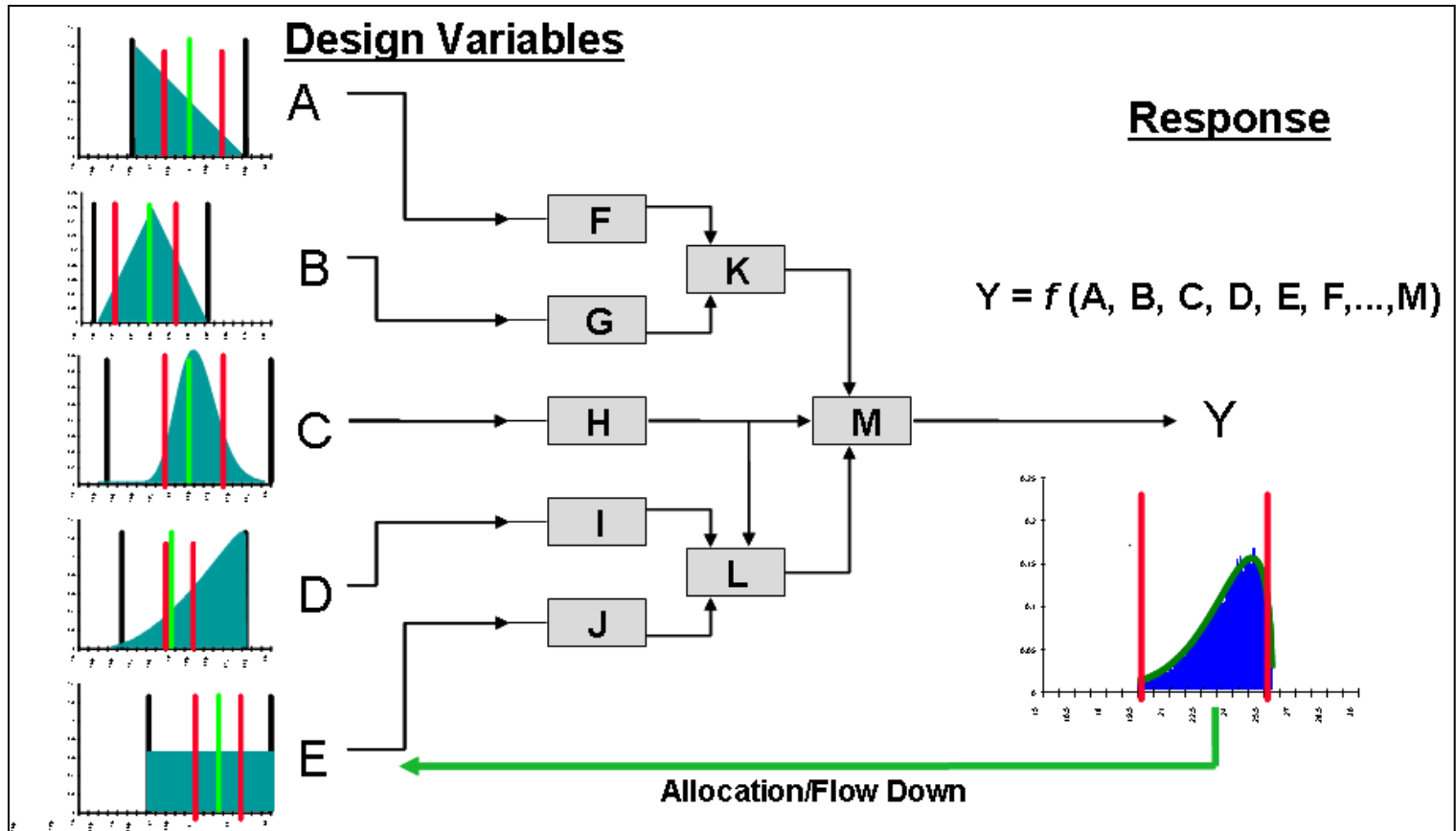


DOE Enables Critical Parameter Management (CPM)

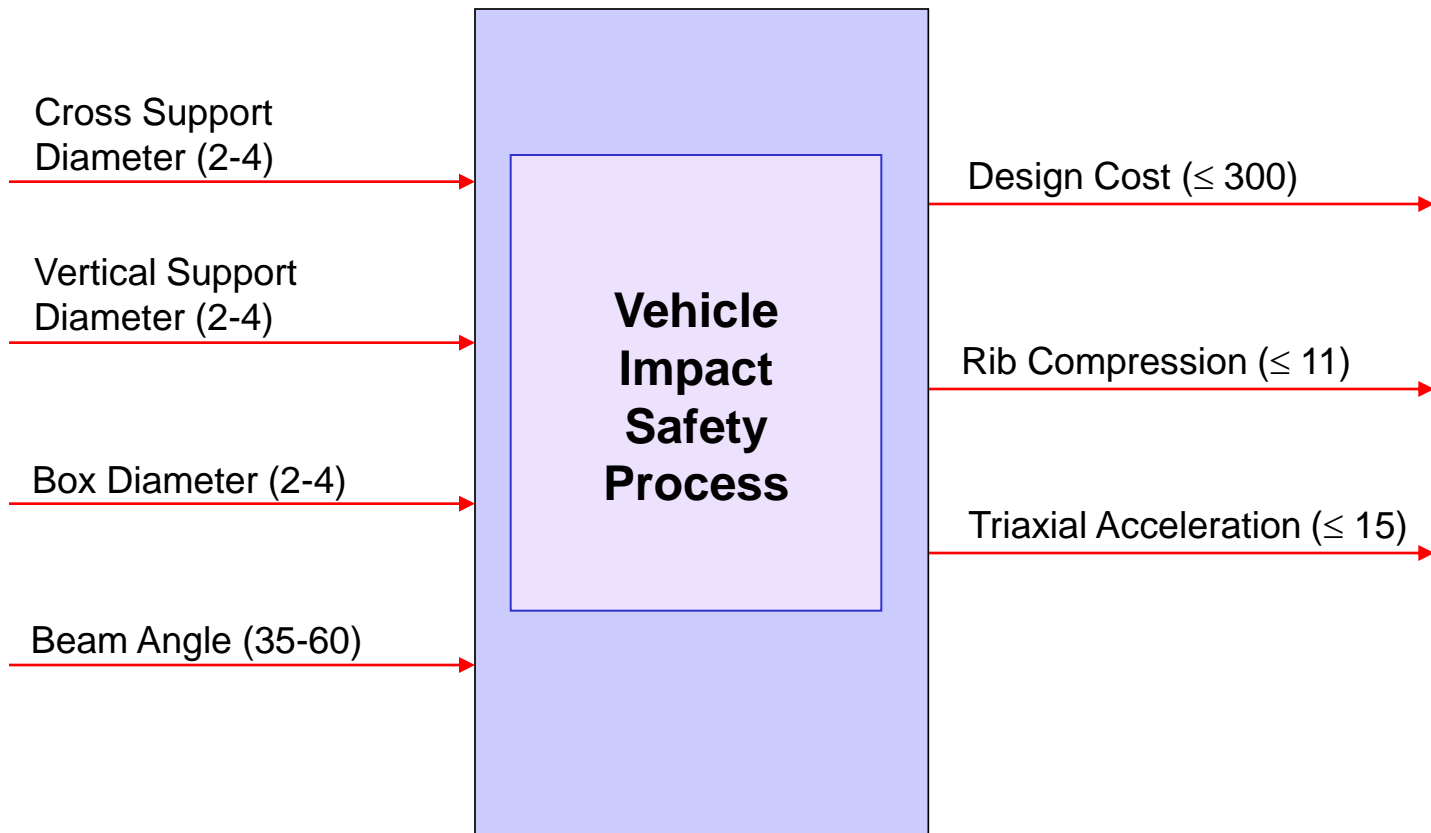
CPM is a systems engineering best practice that is extremely useful in managing, analyzing, and reporting technical product performance. It is also very useful in decomposing COIs and developing linkages between measures and task capabilities/system attributes.



DOE Enables the Composition of Functions



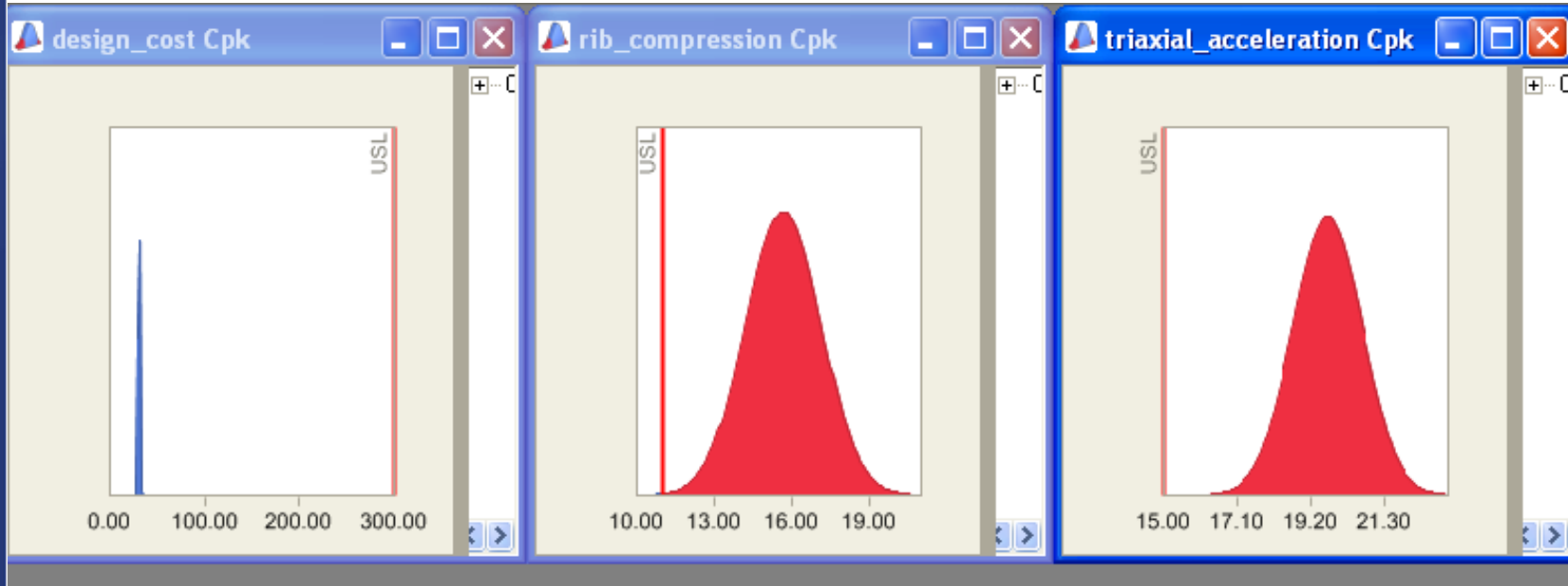
Multiple Response Optimization Simulation* Example



* From **SimWare Pro** by Philip Mayfield and Digital Computations

Multiple Response Optimization (cont.)

Capability Prior to Optimization



Input Controls

Control Set 1

3.000 3.00 2.00 40.00

Cross Support Diameter (2 to 4)

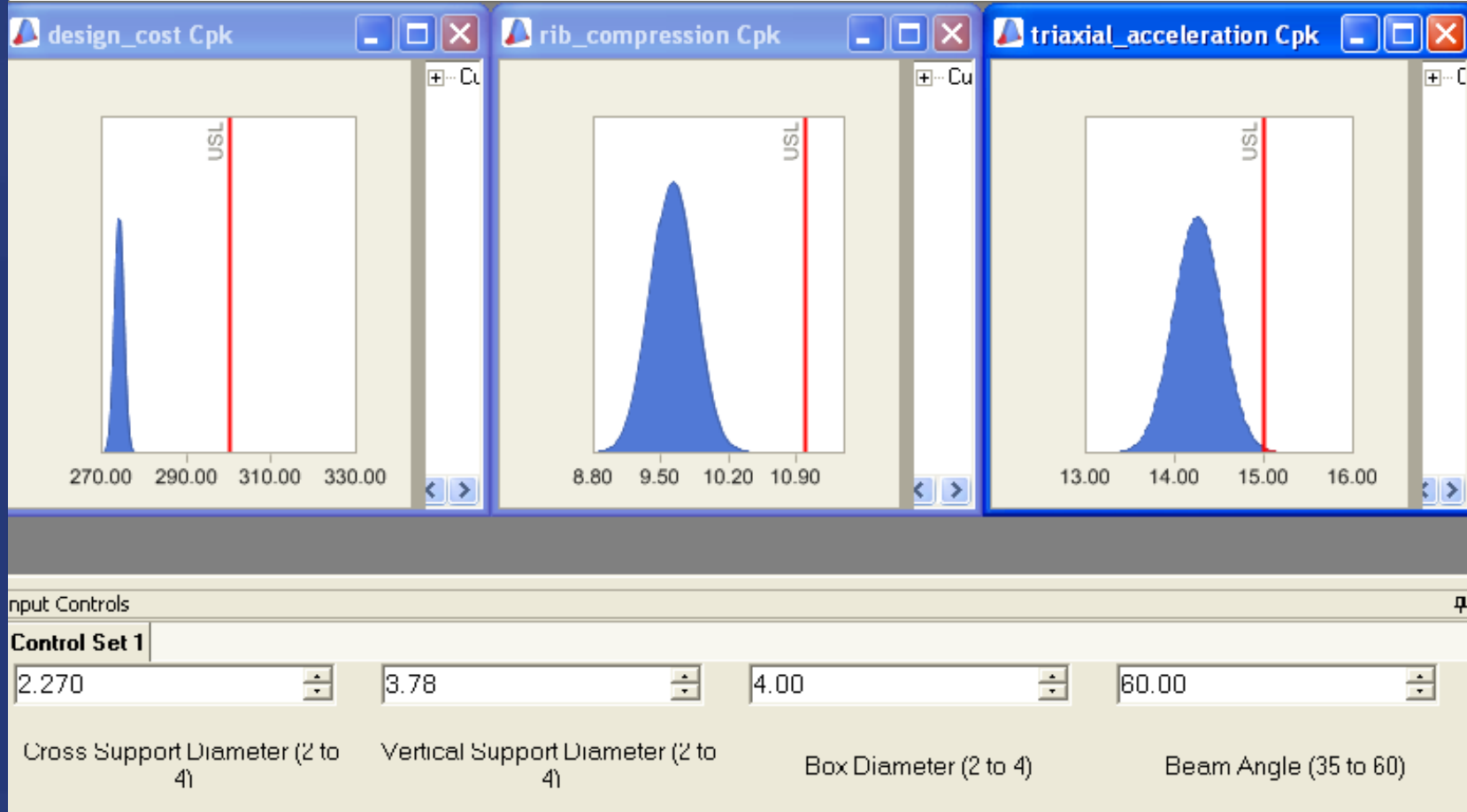
Vertical Support Diameter (2 to 4)

Box Diameter (2 to 4)

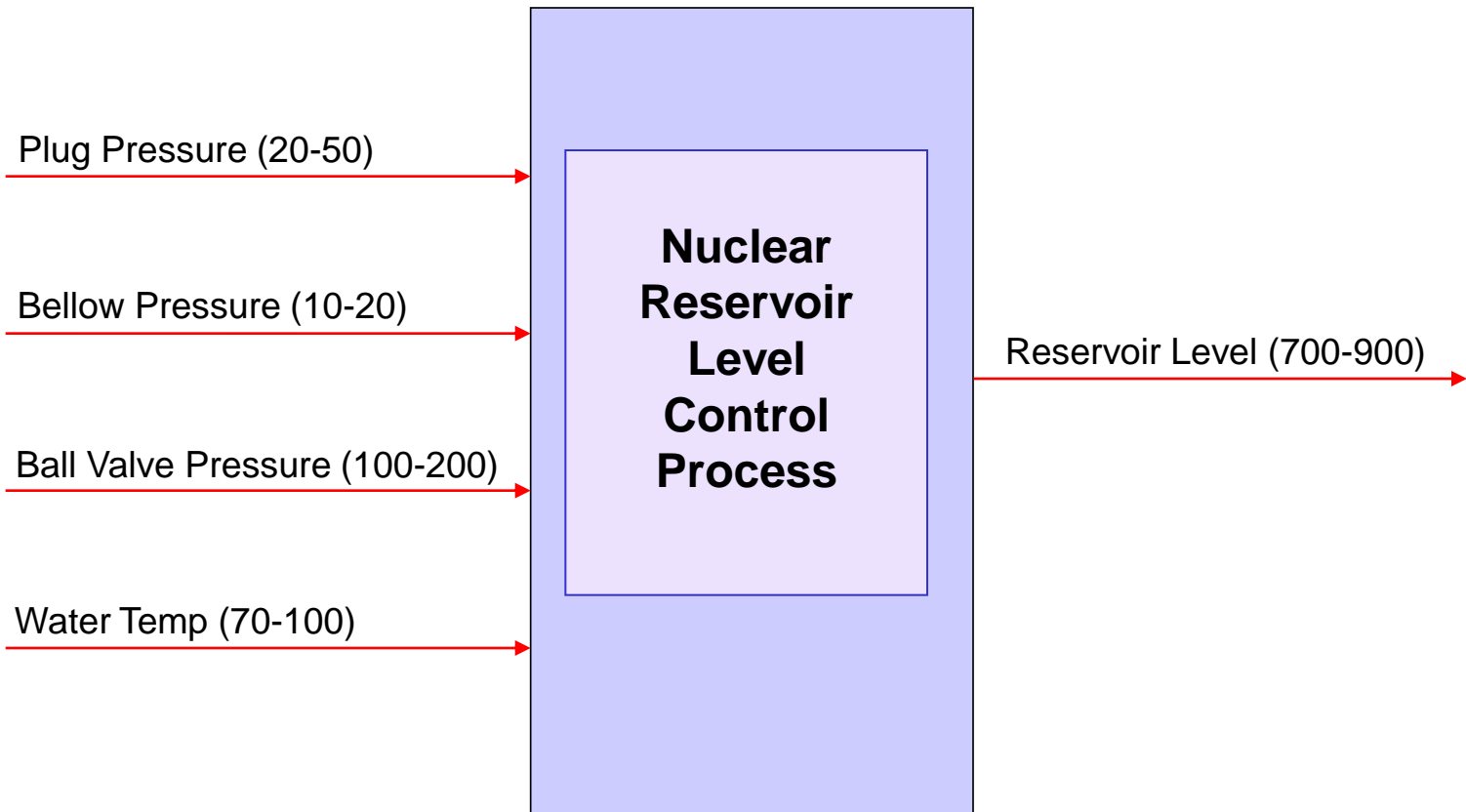
Beam Angle (35 to 60)

Multiple Response Optimization (cont.)

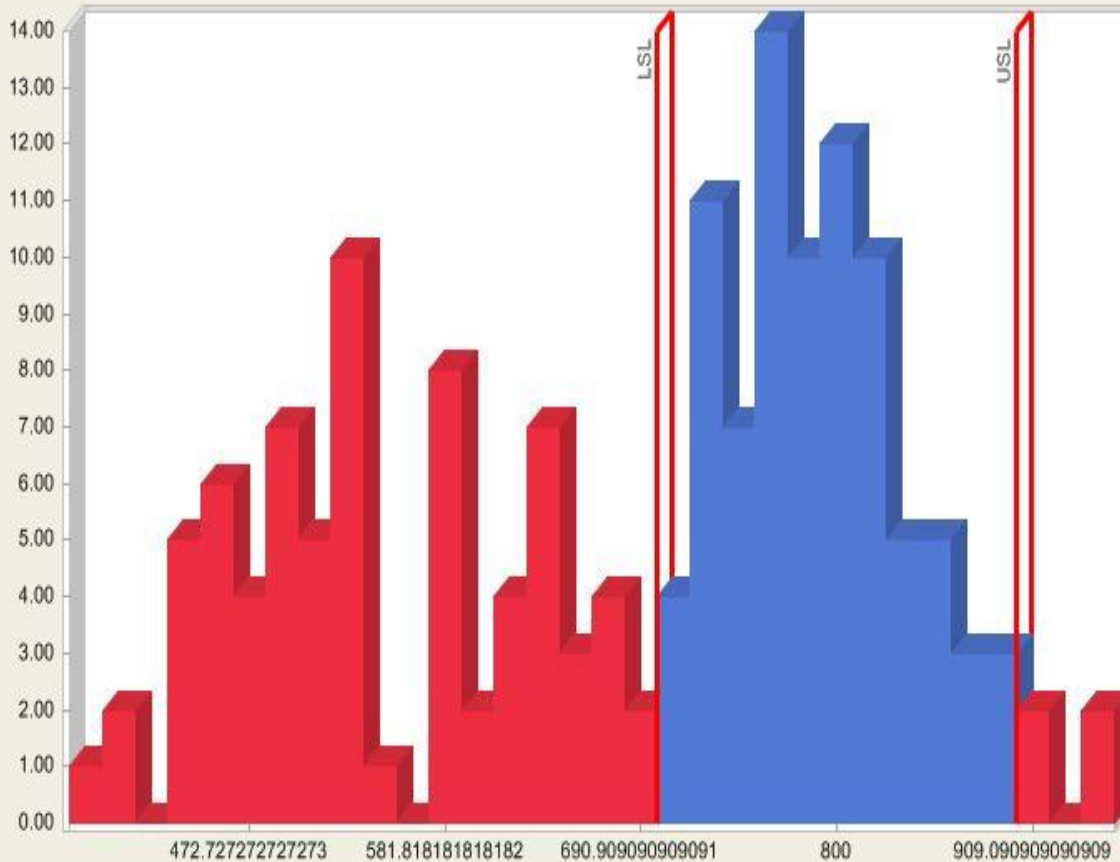
Capability After Optimization



Robust (Parameter) Design Simulation* Example



* From **SimWare Pro** by Philip Mayfield and Digital Computations



Current Data
 n = 159
 Mean = 681.9
 Standard Deviation = 141.6
 LSL = 700
 USL = 900
 Cp = 0.2354
 Cpk = -0.0427
 DPM = 612,650
 Sig Cap = 1.214

Input Controls

Control Set 1

50.0

Plug Pressure (20 to 50)

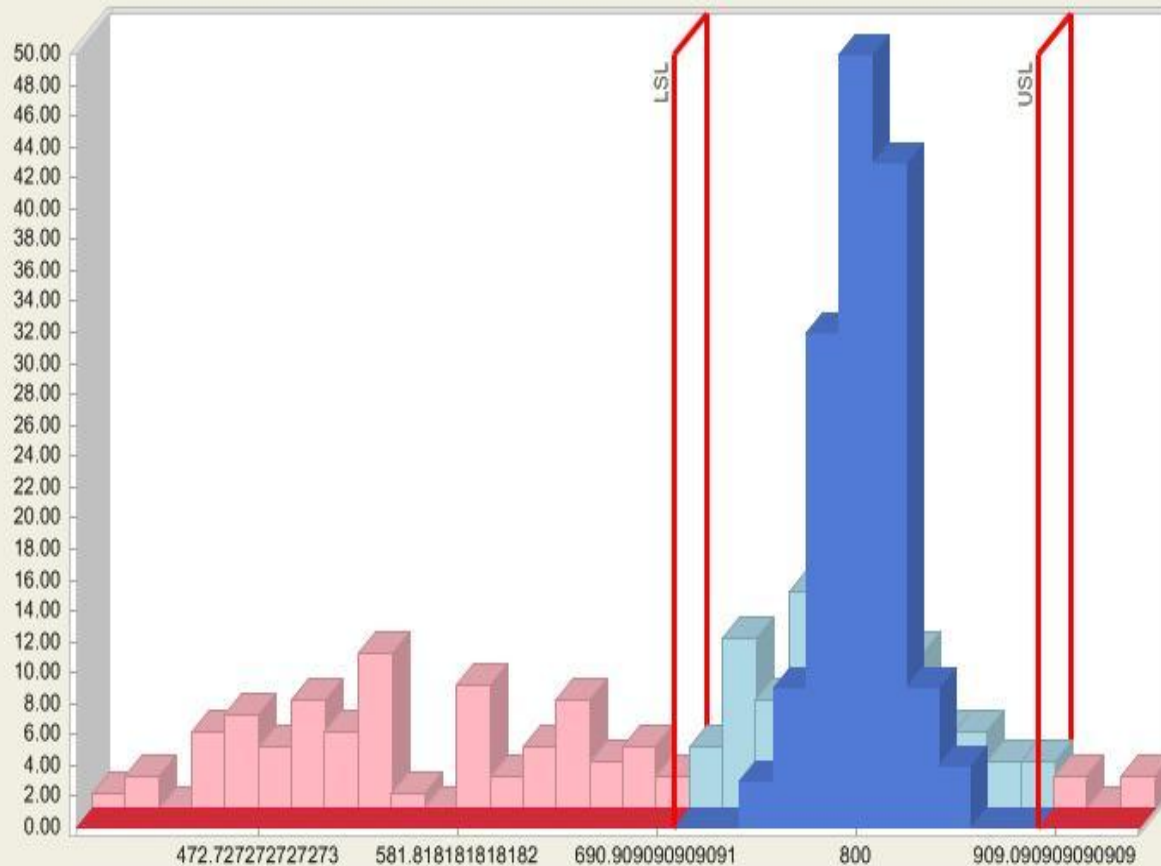
12.00

Bellow Pressure (10 to 20)

145

Ball Valve Pressure (100 to 200)





Current Data
 n = 150
 Mean = 802
 Standard Deviation = 21.56
 LSL = 700
 USL = 900
 Cp = 1.546
 Cpk = 1.516
 DPM = 3.829
 Sig Cap = 5.975

Memorized Data
 n = 159
 Mean = 681.9
 Standard Deviation = 141.6
 LSL = 700
 USL = 900
 Cp = 0.2354
 Cpk = -0.0427
 DPM = 612,650
 Sig Cap = 1.214

Input Controls

Control Set 1

21.0

Plug Pressure (20 to 50)

20.00

Bellow Pressure (10 to 20)

137

Ball Valve Pressure (100 to 200)



Water Temp (Expensive to Control)

Introduction to High Throughput Testing (HTT)

- A recently developed technique based on combinatorics
- Used to test myriad combinations of many factors (typically qualitative) where the factors could have many levels
- Uses a minimum number of runs or combinations to do this
- Software (e.g., ProTest) is needed to select the minimal subset of all possible combinations to be tested so that all 2-way combinations are tested.
- HTT is not a DOE technique, although the terminology is similar
- A run or row in an HTT matrix is, like DOE, a combination of different factor levels which, after being tested, will result in a successful or failed run
- HTT has its origins in the pharmaceutical business where in drug discovery many chemical compounds are combined together (combinatorial chemistry) at many different strengths to try to produce a reaction.
- Other industries are now using HTT, e.g., software testing, materials discovery, integration and functionality testing (see example on next page).

Submarine Threat Detection Example

- Suppose we want to perform a verification test with the following 7 input factors (with their respective settings):
 - Submarine Type (S1, S2, S3)
 - Ocean Depth (Shallow, Deep, Very Deep)
 - Sonar Type (Active, Passive)
 - Target Depth (Surface, Shallow, Deep, Very Deep)
 - Sea Bottom (Rock, Sand, Mud)
 - Control Mode (Autonomous, Manual)
 - Ocean Current (Strong, Moderate, Minimal)

- All possible combinations would involve how many runs in the test?

- If we were interested in testing all pairs only, how many runs would be in the test? Pro Test generated the following test matrix.

Submarine Threat Detection Example (cont.)

The following 15 test cases will test all pairwise combinations.

	Factor_A	Factor_B	Factor_C	Factor_D	Factor_E	Factor_F	Factor_G
Factor Name	Submarine Type	Ocean Depth	Sonar Type	Target Depth	Sea Bottom	Control Mode	Ocean Current
Case 1	S3	Deep	Passive	Very Deep	Mud	Manual	Minimal
Case 2	S1	Very Deep	Passive	Surface	Rock	Autonomous	Strong
Case 3	S2	Shallow	Active	Shallow	Rock	Manual	Moderate
Case 4	S2	Deep	Passive	Deep	Sand	Autonomous	Moderate
Case 5	S1	Shallow	Active	Surface	Sand	Manual	Minimal
Case 6	S1	Very Deep	Passive	Shallow	Mud	Autonomous	Minimal
Case 7	S3	Very Deep	Active	Deep	Mud	Manual	Strong
Case 8	S2	Very Deep	Active	Very Deep	Sand	Autonomous	Strong
Case 9	S3	Shallow	Passive	Shallow	Mud	Autonomous	Strong
Case 10	S3	Deep	Active	Surface	Rock	Manual	Moderate
Case 11	S1	Shallow	Active	Deep	Rock	Autonomous	Minimal
Case 12	S1	Deep	Passive	Very Deep	Rock	Manual	Moderate
Case 13	S2	Very Deep	Active	Surface	Mud	Autonomous	Moderate
Case 14	S3	Deep	Active	Shallow	Sand	Manual	Strong
Case 15	S2	Shallow	Active	Very Deep	Rock	Manual	Minimal

Command & Control Test Example

(15 factors each at various levels)

Total Combinations: 20,155,392

Variable or Factor	Levels	(# of levels)
Mission Snapshots	Entry, Operations, Consolidation	(3)
Network Size	10 Nodes, 50 Nodes, 100 Nodes	(3)
Network Loading	Nominal, 2X, 4X	(3)
Movement Posture	ATH, OTM1, OTM2	(3)
SATCOM Band	Ku, Ka, Combo	(3)
SATCOM Look Angle	0, 45, 75	(3)
Link Degradation	0%, 5%, 10%, 20%	(4)
Node Degradation	0%, 5%, 10%, 20%	(4)
EW	None, Terrestrial, GPS	(3)
Interoperability	Joint Services, NATO	(2)
IA	None, Spoofing, Hacking, Flooding	(4)
Security	NIPR, SIPIR	(2)
Message Type	Data, Voice, Video	(3)
Message Size	Small, Medium, Large, Mega	(4)
Distance Between Nodes	Short, Average, Long	(3)

Command & Control Test Example

(All Pairs Testing from ProTest generates 26 test cases)

	Factor_A	Factor_B	Factor_C	Factor_D	Factor_E	Factor_F	Factor_G	Factor_H	Factor_I	Factor_J	Factor_K	Factor_L	Factor_M	Factor_N	Factor_O
Factor Name	Mission	Network Size	Network Load	Movement	SATCOM Band	SATCOM Angle	Link Degradation	Node Degradation	EW	Interoperability	IA	Security	Message Type	Size of Message	Node Distance
Case 1	Entry	100 nodes	4X	OTM2	Combo	0	0%	0%	None	NATO	None	SIPIR	Voice	Medium	Short
Case 2	Consolidation	10 nodes	Normal	ATH	Ka	45	5%	5%	GPS	NATO	Spoofing	NIPR	Video	Large	Normal
Case 3	Operation	50 nodes	2X	OTM1	Ku	75	20%	20%	Terrestrial	Joint Serv	Hacking	NIPR	Voice	Small	Long
Case 4	Entry	50 nodes	2X	ATH	Ku	45	10%	10%	None	NATO	Flooding	NIPR	Data	Mega	Short
Case 5	Operation	100 nodes	Normal	OTM1	Combo	75	10%	10%	GPS	NATO	Spoofing	SIPIR	Data	Small	Normal
Case 6	Operation	10 nodes	4X	OTM2	Combo	45	0%	5%	Terrestrial	Joint Serv	None	NIPR	Video	Mega	Long
Case 7	Consolidation	100 nodes	4X	ATH	Ka	75	20%	10%	Terrestrial	NATO	Hacking	SIPIR	Video	Medium	Long
Case 8	Operation	10 nodes	Normal	ATH	Ka	0	20%	0%	Terrestrial	Joint Serv	Flooding	NIPR	Data	Large	Short
Case 9	Consolidation	10 nodes	2X	OTM2	Ku	45	5%	20%	None	Joint Serv	Flooding	SIPIR	Voice	Medium	Normal
Case 10	Consolidation	50 nodes	2X	OTM1	Combo	0	0%	20%	GPS	NATO	None	NIPR	Data	Mega	Normal
Case 11	Entry	50 nodes	Normal	OTM2	Ka	75	10%	5%	GPS	Joint Serv	Hacking	SIPIR	Voice	Large	Long
Case 12	Entry	50 nodes	4X	OTM1	Ku	0	5%	0%	None	Joint Serv	Spoofing	SIPIR	Video	Small	Long
Case 13	Consolidation	100 nodes	4X	OTM2	Ku	45	20%	5%	GPS	Joint Serv	Flooding	NIPR	Data	Small	Short
Case 14	Entry	10 nodes	2X	OTM1	Ka	75	5%	0%	None	Joint Serv	Hacking	SIPIR	Data	Mega	Normal
Case 15	Entry	50 nodes	2X	ATH	Ka	75	0%	20%	Terrestrial	NATO	Spoofing	NIPR	Video	Large	Short
Case 16	Consolidation	10 nodes	4X	ATH	Ku	0	10%	20%	Terrestrial	NATO	None	NIPR	Video	Small	Normal
Case 17	Operation	50 nodes	Normal	OTM1	Ku	75	0%	5%	None	Joint Serv	Flooding	NIPR	Data	Medium	Short
Case 18	Operation	10 nodes	Normal	OTM1	Ka	75	20%	10%	None	Joint Serv	None	SIPIR	Video	Large	Normal
Case 19	Operation	100 nodes	2X	OTM2	Combo	0	5%	10%	Terrestrial	NATO	Hacking	SIPIR	Data	Large	Short
Case 20	Consolidation	100 nodes	Normal	ATH	Combo	0	20%	20%	Terrestrial	Joint Serv	Spoofing	NIPR	Voice	Mega	Short
Case 21	Consolidation	50 nodes	2X	OTM1	Ka	45	10%	0%	GPS	Joint Serv	Spoofing	SIPIR	Data	Medium	Normal
Case 22	Entry	100 nodes	Normal	OTM1	Combo	0	20%	5%	GPS	NATO	Flooding	NIPR	Video	Medium	Long
Case 23	Operation	10 nodes	Normal	ATH	Ka	45	0%	10%	None	NATO	Hacking	SIPIR	Voice	Small	Normal
Case 24	Entry	50 nodes	4X	ATH	Ku	45	5%	20%	None	NATO	None	NIPR	Video	Large	Long
Case 25	Consolidation	10 nodes	2X	ATH	Ku	75	10%	5%	None	Joint Serv	Spoofing	NIPR	Data	Large	Long
Case 26	Consolidation	100 nodes	Normal	OTM2	Combo	45	5%	20%	GPS	Joint Serv	Spoofing	NIPR	Voice	Mega	Normal

HTT Applications

- **Reducing the cost and time of testing while maintaining adequate test coverage**
- **Integration, interoperability and functionality testing**
- **Creating a test plan to stress a product and discover problems**
- **Prescreening before a large DOE to ensure all 2-way combinations are feasible before discovering, midway through an experiment, that certain combinations are not feasible**
- **Developing an “outer array” of noise combinations to use in a robust design DOE when the number of noise factors and settings is large**

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